

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/784,274	<b>Applicant(s)/Patent under Reexamination</b>  TAKAHASHI ET AL.
	<b>Examiner</b>  Don P. Le	<b>Art Unit</b>  2819

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
326	37, 39	5/9/2005	DL